SEP 1 5 2005

.

SHEET 1 OF 1

(Modified)		U.S. DEPARTMENT PATENT AND TRA	DEMORK OFFICE	273626US2PCT	ATTY DOCKET NO.		SERIAL NO.			
, many manufacture.					10/540,003					
¥ LIST OF	REFE	RENCES CITED BY AF	PPLICANT	APPLICANT Jerome HAZART						
				FILING DATE		GROUP				
				June 21, 2005		GROOP				
<u> </u>				U.S. PATENT DOCUMENTS	<del></del>	L				
EXAMINER		DOCUMENT	<del></del>	T. C.G. F. ATERT DOGGINERATO	<u> </u>	SUB	FILING DATE			
INITIAL		NUMBER	DATE	NAME	CLASS	CLASS	IF APPROPRIATE			
N	AA	5,956,145	09/21/99	GREEN, Steven E. et al.						
	AB		<u> </u>							
	AC									
	AD									
	AE									
	AF		ļ				/			
	AG		<u> </u>	/		/	<b>′</b>			
	AH			1						
	Al									
	Ą				/					
	AK		\		/_	ļļ				
	AL		<u> </u>							
	AM	1								
			FC	DREIGN PATENT DOCUMENTS						
	DOCUMENT DATE COUNTRY TRANSLATION									
ı		DOCOMENT	I DATE	COLINTRY			TRANSLATION			
		NUMBER	DATE	COUNTRY		YES				
p	AN		DATE 04/04/02	COUNTRY						
M	AN	NUMBER 02/27288	04/04/02		rtinent Pages, e	YES	s no			
n	AN	NUMBER 02/27288 OTHER RI D. BHATTACHARYY	04/04/02 EFERENCES A et al.: "Spect	WO (Including Author, Title, Date, Per		YES	S NO NO			
PV PV		NUMBER  02/27288  OTHER RI  D. BHATTACHARYY/ 419-424, March 2001. Jean GARRIGUES: "I	04/04/02 EFERENCES A et al.: "Spect XP-00295410	WO (Including Author, Title, Date, Per	lielectric coating	YES tc.) s", Vacuum	S NO NO			
PV IN	AO	NUMBER  02/27288  OTHER RI  D. BHATTACHARYYY 419-424, March 2001. Jean GARRIGUES: "I XP-002254500  Babar K. MINHAS et a	04/04/02  EFERENCES A et al.: "Spect XP-00295410 a methode de	WO (Including Author, Title, Date, Pertroscopic ellipsometry of multilayer of the selements finis", 'Online!, pages 1-tric scatterometry for the metrology	fielectric coating	YES tc.) s*, Vacuum 2.	NO NO n, Vol. 60, No. 4, pages			
PV IN	AO AP	NUMBER  02/27288  OTHER RI  D. BHATTACHARYYY 419-424, March 2001. Jean GARRIGUES: "IL XP-002254500  Babar K. MINHAS et a Vol. 37, No. 22, pages Fred L. TERRY, Jr.: "/	04/04/02  EFERENCES  A et al.: "Spect XP-00295410  a methode de al.: "Ellipsomet 5 5112-5115, A A modified han	WO (Including Author, Title, Date, Per troscopic ellipsometry of multilayer of 24 es elements finis", 'Online!, pages 1-	dielectric coating 83, January 200 of sub-0.1-µm-lin	YES tc.) s*, Vacuum 2.	NO N			
N	AO AP AQ	NUMBER  02/27288  OTHER RI  D. BHATTACHARYYY 419-424, March 2001. Jean GARRIGUES: "IL XP-002254500  Babar K. MINHAS et a Vol. 37, No. 22, pages Fred L. TERRY, Jr.: "/ Journal of Applied Phy	04/04/02  EFERENCES  A et al.: "Spect XP-00295410  a methode de al.: "Ellipsomet 5 5112-5115, A A modified han ysics, Vol. 70,	WO (Including Author, Title, Date, Pertroscopic ellipsometry of multilayer of the selements finis", 'Online!, pages 1-tric scatterometry for the metrology (August 1, 1998, XP-001162836) monic oscillator approximation sche	dielectric coating.  83, January 200  of sub-0.1-µm-lin  me for the dielectric	YES tc.) s*, Vacuum 2. sewidth structric consta	NO N			
PV IN	AO AP AQ AR	NUMBER  02/27288  OTHER RI  D. BHATTACHARYYY 419-424, March 2001. Jean GARRIGUES: "I XP-002254500  Babar K. MINHAS et a Vol. 37, No. 22, pages Fred L. TERRY, Jr.: "/ Journal of Applied Phy R.M.A. AZZAM and N	04/04/02  EFERENCES  A et al.: "Spect    XP-00295410  a methode de  al.: "Ellipsomet    5112-5115, A    modified han    ysics, Vol. 70,  .M. BASHARA	WO (Including Author, Title, Date, Pertroscopic ellipsometry of multilayer of the selements finis", 'Onlinel, pages 1-tric scatterometry for the metrology (August 1, 1998. XP-001162836) monic oscillator approximation sche No. 1, pages 409-417, July 1, 1991	dielectric coating.  83, January 200  of sub-0.1-µm-lin  me for the dielectric	YES tc.) s*, Vacuum 2. sewidth structric consta	NO NO NO. 4, pages  victures", Applied Optics, ints of AlxGa1-xAs",			
PV IN	AO AP AQ AR AS	NUMBER  02/27288  OTHER RI  D. BHATTACHARYYY 419-424, March 2001 Jean GARRIGUES: "L XP-002254500 Babar K. MINHAS et a Vol. 37, No. 22, pages Fred L. TERRY, Jr.: "Journal of Applied Ph R.M.A. AZZAM and N  Max Wolf BORN: "Print A. R. FOROUHI: "Opt	04/04/02  EFERENCES A et al.: "Spect. XP-00295410 a methode de al.: "Ellipsomet s 5112-5115, A A modified hor, ysics, Vol. 70, M. BASHARA nciples of Optic	WO  (Including Author, Title, Date, Pertroscopic ellipsometry of multilayer of the selements finis", 'Online!, pages 1-tric scatterometry for the metrology of August 1, 1998. XP-001162836 monic oscillator approximation sche No. 1, pages 409-417, July 1, 1991 x: "ELLIPSOMETRY AND POLARIZ cs", 7th, exp. ed. 1999.	dielectric coating.  83. January 200  of sub-0.1-µm-lir  me for the dielectric  ED LIGHT*, Cha	YES tc.) s", Vacuum 2. sewidth structric consta	NO N			
PV   PV   PV   PV   PV   PV   PV   PV	AO AP AQ AR AS	NUMBER  02/27288  OTHER R  D. BHATTACHARYY/ 419-424, March 2001. Jean GARRIGUES: "L XP-002254500  Babar K. MINHAS et a Vol. 37, No. 22, pages Fred L. TERRY, Jr.: "/ Journal of Applied Phy R.M.A. AZZAM and N  Max Wolf BORN: "Print A. R. FOROUHI: "Opt B, Vol. 34, No. 10, pages	04/04/02  EFERENCES A et al.: "Spect. XP-00295410 a methode de al.: "Ellipsomet s 5112-5115, A A modified han ysics, Vol. 70, M. BASHARA nciples of Optic ical dispersion ges 7018-7026 EUKOLSKY, V	WO  (Including Author, Title, Date, Per proscopic ellipsometry of multilayer of the selements finis", 'Onlinel, pages 1-tric scatterometry for the metrology of August 1, 1998. XP-001162836 monic oscillator approximation sche No. 1, pages 409-417, July 1, 1991. TELLIPSOMETRY AND POLARIZ CS", 7th, exp. ed. 1999.  Telations for amorphous semicondus, November 15, 1986.  W. T. VETTERLING, B. P. FLANNE	dielectric coating.  83, January 200  of sub-0.1-µm-lin  ime for the dielectric  ED LIGHT*, Cha	YES tc.) s", Vacuum 2. newidth structric consta	NO N			
PV	AO AP AQ AR AS AT AU	NUMBER  02/27288  OTHER RI  D. BHATTACHARYY/ 419-424, March 2001.  Jean GARRIGUES: "I XP-002254500  Babar K. MINHAS et a Vol. 37, No. 22, pages Fred L. TERRY, Jr.: "/ Journal of Applied Phy R.M.A. AZZAM and N  Max Wolf BORN: "Pri A. R. FOROUHI: "Opt B, Vol. 34, No. 10, pag W. H. PRESS, S. A. T Computing", 2 <sup>rd</sup> Editio	A et al.: "Spect XP-00295410  a methode de al.: "Ellipsomet 5 5112-5115, A modified hardysics, Vol. 70, .M. BASHARA nciples of Opticical dispersion ges 7018-7026 EUKOLSKY, Von, Chapter 3, 1	WO  (Including Author, Title, Date, Pertroscopic ellipsometry of multilayer of the selements finis", 'Onlinel, pages 1-tric scatterometry for the metrology (August 1, 1998, XP-001162836) monic oscillator approximation sche No. 1, pages 409-417, July 1, 1991; "ELLIPSOMETRY AND POLARIZES", 7th, exp. ed. 1999.  Trelations for amorphous semicondus, November 15, 1986.  W. T. VETTERLING, B. P. FLANNE pages 105-123.	dielectric coating.  83. January 200 of sub-0.1-µm-lin rme for the dielectric ED LIGHT*, Characters and amorp	yes tc.) s", Vacuum 2. tewidth structric consta	NO N			
P	AO AP AQ AR AS AT AU	NUMBER  02/27288  OTHER RI  D. BHATTACHARYY/ 419-424, March 2001.  Jean GARRIGUES: "I XP-002254500  Babar K. MINHAS et a Vol. 37, No. 22, pages Fred L. TERRY, Jr.: "/ Journal of Applied Phy R.M.A. AZZAM and N  Max Wolf BORN: "Pri A. R. FOROUHI: "Opt B, Vol. 34, No. 10, pag W. H. PRESS, S. A. T Computing", 2 <sup>rd</sup> Editio	A et al.: "Spect XP-00295410 .a methode de al.: "Ellipsomet 5 5112-5115, A modified hardysics, Vol. 70, .M. BASHARA nciples of Opticical dispersion ges 7018-7026 EUKOLSKY, Von, Chapter 3, 1	WO  (Including Author, Title, Date, Pertroscopic ellipsometry of multilayer of the selements finis", 'Onlinel, pages 1-tric scatterometry for the metrology (August 1, 1998, XP-001162836) monic oscillator approximation sche No. 1, pages 409-417, July 1, 1991; "ELLIPSOMETRY AND POLARIZ CS", 7th, exp. ed. 1999.  Telations for amorphous semicondum, November 15, 1986.  W. T. VETTERLING, B. P. FLANNE pages 105-123.  W. T. VETTERLING, B. P. FLANNE	dielectric coating.  83. January 200 of sub-0.1-µm-lin rme for the dielectric ED LIGHT*, Characters and amorp	tc.) s*, Vacuum 2. tric consta spter 6, pag bhous diele Recipes in Recipes in	NO N			
P	AO AP AQ AR AS AT AU AV	NUMBER  02/27288  OTHER RI  D. BHATTACHARYYY 419-424, March 2001. Jean GARRIGUES: "I XP-002254500  Babar K. MINHAS et a Vol. 37, No. 22, pages Fred L. TERRY, Jr.: "/ Journal of Applied Phy R.M.A. AZZAM and N  Max Wolf BORN: "Pri A. R. FOROUHI: "Opt B, Vol. 34, No. 10, pag W. H. PRESS, S. A. T Computing", 2 <sup>rd</sup> Editio W. H. PRESS, S. A. T	A et al.: "Spect XP-00295410 .a methode de al.: "Ellipsomet 5 5112-5115, A modified hardysics, Vol. 70, .M. BASHARA nciples of Opticical dispersion ges 7018-7026 EUKOLSKY, Von, Chapter 3, 1	WO  (Including Author, Title, Date, Pertroscopic ellipsometry of multilayer of the selements finis", 'Onlinel, pages 1-tric scatterometry for the metrology (August 1, 1998, XP-001162836) monic oscillator approximation sche No. 1, pages 409-417, July 1, 1991; "ELLIPSOMETRY AND POLARIZ CS", 7th, exp. ed. 1999.  Telations for amorphous semicondum, November 15, 1986.  W. T. VETTERLING, B. P. FLANNE pages 105-123.  W. T. VETTERLING, B. P. FLANNE	dielectric coating.  83, January 200 of sub-0.1-µm-lin me for the dielectric coating.  ED LIGHT*, Characters and amorp  RY: "Numerical in the coating of the	tc.) s*, Vacuum 2. tric consta spter 6, pag bhous diele Recipes in Recipes in	NO N			
P	AO AP AQ AR AS AT AU AV	NUMBER  02/27288  OTHER RI  D. BHATTACHARYYY 419-424, March 2001. Jean GARRIGUES: "I XP-002254500  Babar K. MINHAS et a Vol. 37, No. 22, pages Fred L. TERRY, Jr.: "/ Journal of Applied Phy R.M.A. AZZAM and N  Max Wolf BORN: "Pri A. R. FOROUHI: "Opt B, Vol. 34, No. 10, pag W. H. PRESS, S. A. T Computing", 2 <sup>rd</sup> Editio W. H. PRESS, S. A. T	A et al.: "Spect XP-00295410 .a methode de al.: "Ellipsomet 5 5112-5115, A modified hardysics, Vol. 70, .M. BASHARA nciples of Opticical dispersion ges 7018-7026 EUKOLSKY, Von, Chapter 3, 1	WO  (Including Author, Title, Date, Pertroscopic ellipsometry of multilayer of the selements finis", 'Onlinel, pages 1-tric scatterometry for the metrology (August 1, 1998, XP-001162836) monic oscillator approximation sche No. 1, pages 409-417, July 1, 1991; "ELLIPSOMETRY AND POLARIZ CS", 7th, exp. ed. 1999.  Telations for amorphous semicondum, November 15, 1986.  W. T. VETTERLING, B. P. FLANNE pages 105-123.  W. T. VETTERLING, B. P. FLANNE	dielectric coating.  83, January 200 of sub-0.1-µm-lin one for the dielectric ED LIGHT*, Characters and amorp RY: "Numerical I	yes tc.) s*, Vacuum 2. tewidth structric consta	NO N			
P	AO AP AQ AR AS AT AU AV AW	NUMBER  02/27288  OTHER RI  D. BHATTACHARYYY 419-424, March 2001. Jean GARRIGUES: "I XP-002254500  Babar K. MINHAS et a Vol. 37, No. 22, pages Fred L. TERRY, Jr.: "/ Journal of Applied Phy R.M.A. AZZAM and N  Max Wolf BORN: "Pri A. R. FOROUHI: "Opt B, Vol. 34, No. 10, pag W. H. PRESS, S. A. T Computing", 2 <sup>rd</sup> Editio W. H. PRESS, S. A. T	A et al.: "Spect XP-00295410 .a methode de al.: "Ellipsomet 5 5112-5115, A modified hardysics, Vol. 70, .M. BASHARA nciples of Opticical dispersion ges 7018-7026 EUKOLSKY, Von, Chapter 3, 1	WO  (Including Author, Title, Date, Pertroscopic ellipsometry of multilayer of the selements finis", 'Onlinel, pages 1-tric scatterometry for the metrology (August 1, 1998, XP-001162836) monic oscillator approximation sche No. 1, pages 409-417, July 1, 1991; "ELLIPSOMETRY AND POLARIZ CS", 7th, exp. ed. 1999.  Telations for amorphous semicondum, November 15, 1986.  W. T. VETTERLING, B. P. FLANNE pages 105-123.  W. T. VETTERLING, B. P. FLANNE	dielectric coating.  83, January 200 of sub-0.1-µm-lin one for the dielectric ED LIGHT*, Characters and amorp RY: "Numerical I	yes tc.) s*, Vacuum 2. tewidth structric consta	NO N			

LIST OF REFERENCES CITED BY APPLICANT  LIST OF REFERENCES CITED BY APPLICANT  FILING DATE  June 21, 2005  U.S. PATENT DOCUMENTS  ATTY DUCKET NO.  273626US2PCT  10/540,003  APPLICANT  Jerome HAZART  FILING DATE  JUNE 21, 2005  U.S. PATENT DOCUMENTS				— (9)	-6/					7		
LIST OF REFERENCES CITED BY APPLICANT  LIST OF REFERENCES			U.S. DELATINE HILL SOMMERCE			1		SERIAL NO. 10/540,003				
UST OF REFERENCES CITED BY APPLICANT    Jaro	Modif	led)										
FILING DATE JUS. 21, 2005  U.S. PATENT DOCUMENTS  EXAMINER INITIAL AN US2008/0077386 A1 DATE AB AC AD AD AE AF AF AG AG AH AN						APPLICANT						
U.S. PATENT DOCUMENTS  EXAMINER INITIAL  DOCUMENT DATE  NAME  CLASS SUB FLING DATE  CLASS CLASS FAPPOPRIATE  AA US2005/0077386 A1 DA/13/06 Hazard  AB AC  AC  AD  AB AC  AF  AG  AF  AG  AF  AG  AH  AI  AI  AI  AI  AN  AN  FOREIGN PATENT DOCUMENTS   FOREIGN PATENT DOCUMENTS  TRANSLATION  YES NO  APP  AQ  APP  AQ  APP  AQ  APP  AQ  AT  THIGH Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et at.; Thin Scild Films, 234 (1993)  THE PREPARENCES (Including Author, Title, Date, Pertinent Pages, etc.)  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  THIGH Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et at.; Thin Scild Films, 234 (1993)  AV  TEllipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  Temperature Deopendence of the InP(001) Bulk and Surface Dislectric Function" Zom et al.; App. Phys. A, 55, 333-339  (1497)  AZ  Additional References sheel(s) attached  Date Considered 2/3/07  Date Considered 2/3/07  Date Considered 2/3/07  Date Considered 2/3/07	- 1	LIST OF F	REFER	ENCES CITED BY APP	PLICANT							
U.S. PATENT DOCUMENTS  U.S. PATENT DOCUMENTS  DATE NAME CLASS SUB FILING DATE FAPPROPRIATE  NAME CLASS SUB FILING DATE FAPPROPRIATE  AA US20060077386 A1 04/13/06 Hazari  AB AC AC AD AC						FILING DATE						
EXAMINER INITIAL  DOCUMENT DATE NAME CLASS SUB FILING DATE FLING DATE COUNTRY  FOREIGN PATENT DOCUMENTS  TRANSLATION YES NO  AND AND FOREIGN PATENT DOCUMENTS  TRANSLATION YES NO  AND AND FOREIGN PATENT DOCUMENTS  TRANSLATION YES NO  AND AND AND FLING DATE COUNTRY TRANSLATION YES NO  AND	ļ.					June 21, 2005		2877				
NUMBER NOUNBER NAME CLASS CLASS   FAPROPRIATE NAME   NUMBER   NUMB						U.S. PATENT DOCUMENTS						
AB AC AD AD AE AF AF AG AG AH AI AI AI AI AN	EXAMINER INITIAL				DATE	NAME	CLASS					
AC  AD  AE  AF  AG  AG  AH  AI  AI  AI  AI  AN  AK  AL  AM  AN  BOCUMENT  NUMBER  DATE  COUNTRY  TRANSLATION  YES  NO  AO  AO  AR  AQ  AR  AG  AG  AR  AG  AG  AR  AG  AG  AR  AG  AG	7	N	AA	US2006/0077386 A1	04/13/06	Hazart	<u> </u>			/		
AD  AE  AF  AG  AG  AH  AI  AI  AI  AI  AN  FOREIGN PATENT DOCUMENTS  FOREIGN PATENT DOCUMENTS  TRANSLATION YES NO  AO  AP  AO  AP  AQ  AR  AR  AR  AS  AT  AU  AV  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  THigh Precision UV-Visible-Near IR Stokes Vector Spectroscopy, "Zetile et al.; Thin Solid Films, 234 (1993)  THIGH Precision UV-Visible-Near IR Stokes Vector Spectroscopy, "Zetile et al.; Thin Solid Films, 234 (1993)  THIGH Precision UV-Visible-Near IR Stokes Vector Spectroscopy, "Zetile et al.; Thin Solid Films, 234 (1993)  THIGH Precision UV-Visible-Near IR Stokes Vector Spectroscopy, "Zetile et al.; Thin Solid Films, 234 (1993)  THIGH Precision UV-Visible-Near IR Stokes Vector Spectroscopy, "Zetile et al.; Thin Solid Films, 234 (1993)  THIGH Precision UV-Visible-Near IR Stokes Vector Spectroscopy, "Zetile et al.; Thin Solid Films, 234 (1993)  AV  Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function* Zorn et al.; App. Phys. A, 85, 333-339 (1997)  AZ  AZ  AZ  Additional References sheet(s) attacher.  Date Considered 2/3/07			AB									
AE  AF  AG  AH  AI  AI  AI  AI  AN  AN  FOREIGN PATENT DOCUMENTS  TRANSLATION YES NO  AO  AP  AQ  AR  AR  AS  AT  AU  AV  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  THigh Precision UV-Visible-Near IR Stokes Vector Spectroscopy, "Zettle et al., Thin Solid Films, 234 (1993)  AW  "High Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al., Thin Solid Films, 234 (1993)  AV  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  "Emperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zom et al.: App. Phys. A, 65, 333-339 (1997)  AZ  AZ  AZ  Additional References sheet(s) attached  Date Considered  2/3/07			AC									
AF  AG  AH  AI  AI  AI  AN  AK  AK  AL  AM  AN  BOCUMENT  NUMBER  AO  AO  AO  AP  AQ  AQ  AR  AS  AS  AT  AU  AV  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  THIGH Precision UV-Visible-Near IR Stokes Vector Spectroscopy, 'Zettle et al.; Thin Solid Films, 234 (1993)  AW  "High Precision UV-Visible-Near IR Stokes Vector Spectroscopy,' Zettle et al.; Thin Solid Films, 234 (1993)  AX  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  "Emperature Deopendence of the InP(001) Bulk and Surface Dielectric Function' Zom et al.; App. Phys. A, 65, 333-339 (1997)  AZ  AZ  AZ  AZ  AZ  AZ  AZ  AZ  AZ  A		-	AD				<u> </u>					
AG  AH  AI  AJ  AX  AK  AK  AK  AN  BOCUMENT  AN  AN  AN  FOREIGN PATENT DOCUMENTS  TRANSLATION  YES  NO  AO  AP  AQ  AQ  AR  AQ  AR  AR  AS  AT  AT  AU  AV  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  THIS Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  THIS Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AX  Tellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  Temperature Deopendence of the inP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339  (1997)  AZ  AZ  AZ  AZ  Additional References sheet(s) attached  Lexaminer  Date Considered 2/3/07			AE				<u> </u>					
AH  AI  AJ  AK  AK  AL  AM  AN  POREIGN PATENT DOCUMENTS  TRANSLATION YES NO  AO  AO  AP  AQ  AR  AR  AS  AT  AU  AV  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  THIS Precision UV-Visible-Near IR Stokes Vector Spectroscopy. Zettle et al., Thin Solid Films, 234 (1993)  AW  "High Precision UV-Visible-Near IR Stokes Vector Spectroscopy." Zettle et al., Thin Solid Films, 234 (1993)  AV  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function* Zom et al.; App. Phys. A, 65, 333-339 (1997)  AZ  AZ  AZ  Additional References sheet(s) attached to the page of the page			AF									
AI  AI  AX  AK  AL  AM  AN  AN  COUNTRY  FOREIGN PATENT DOCUMENTS  FOREIGN PATENT DOCUMENTS  TRANSLATION YES NO  AO  AP  AQ  AR  AS  AT  AU  AV  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  THigh Predision UV-Visible-Near IR Stokes Vector Spectroscopy, "Zettle et al.; Thin Solid Films, 234 (1993)  AW  "High Predision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AX  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339  AY  AZ  Additional References sheet(s) attached Additi			AG				<u> </u>					
AI  AI  AX  AK  AL  AM  AN  AN  COUNTRY  FOREIGN PATENT DOCUMENTS  FOREIGN PATENT DOCUMENTS  TRANSLATION YES NO  AO  AP  AQ  AR  AS  AT  AU  AV  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  THigh Predision UV-Visible-Near IR Stokes Vector Spectroscopy, "Zettle et al.; Thin Solid Films, 234 (1993)  AW  "High Predision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AX  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339  AY  AZ  Additional References sheet(s) attached Additi			АН									
AJ  AK  AL  AM  AN  AN  AN  AN  FOREIGN PATENT DOCUMENTS  FOREIGN PATENT DOCUMENTS  TRANSLATION YES  NO  AO  AP  AQ  AP  AQ  AR  AS  AS  AT  AU  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  THigh Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AW  "High Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AW  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AY  "Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zom et al.; App. Phys. A, 65, 333-339 (1997)  AZ  AZ  AZ  AZ  Additional References sheet(s) attached  Date Considered  Additional References sheet(s) attached  Date Considered  AZ JO 7	_		Al			/						
AK AL AM AN  FOREIGN PATENT DOCUMENTS  FOREIGN PATENT DOCUMENTS  TRANSLATION YES NO  AO AP AP AQ AR AR AS AT AU AV  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  THigh Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AW  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AY  Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339 (1997)  AZ  Date Considered  Date Considered  Date Considered  Date Considered  Date Considered  2/3/07												
AL  AM  AN  FOREIGN PATENT DOCUMENTS  TRANSLATION YES NO  AO  AP  AQ  AR  AS  AT  AU  AV  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  THigh Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AW  Tellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AY  Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zom et al.; App. Phys. A, 65, 333-339  (1997)  AZ  AZ  Date Considered  Additional References sheet(s) attached  Date Considered  2/3/07  Date Considered  Date Considered  2/3/07								V _				
FOREIGN PATENT DOCUMENTS    DOCUMENT   NUMBER   DATE   COUNTRY   TRANSLATION   YES   NO					/			1				
FOREIGN PATENT DOCUMENTS  DOCUMENT NUMBER DATE COUNTRY TRANSLATION YES NO  AO AP AR AS AS AT AT AU AV OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  Whigh Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zeitle et al.; Thin Solid Films, 234 (1993)  AX "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX "Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339 (1997)  AZ Additional References sheet(s) attached bate of the InP(001) Bulk and Surface Dielectric Function and Additional References sheet(s) attached bate of the InP(001) Bulk and Surface Dielectric Function and Additional References sheet(s) attached bate of the InP(001) Bulk and Surface Dielectric Function and Additional References sheet(s) attached by the InP(001) Bulk and Surface Dielectric Function and Additional References sheet(s) attached by the InP(001) Bulk and Surface Dielectric Function and Additional References sheet(s) attached by the InP(001) Bulk and Surface Dielectric Function and Additional References sheet(s) attached by the InP(001) Bulk and Surface Dielectric Function and Additional References sheet(s) attached by the InP(001) Bulk and Surface Dielectric Function and InP(001) Bulk and Surface Diel					+		17					
POREIGN PATENT DOCUMENT NUMBER  AO  AO  AP  AQ  AR  AS  AT  AU  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  TWO WIND AW  "High Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AX  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339 (1997)  AZ  Examiner  Date Considered 2/3/07  Examiner  Date Considered 2/3/07			├──	-	<del>                                     </del>		1					
AO  AO  AO  AP  AQ  AR  AS  AT  AU  AV  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  *High Precision UV-Visible-Near IR Stokes Vector Spectroscopy,* Zettle et al.; Thin Solid Films, 234 (1993)  AW  *Ellipsometry on Very Thick Multilayer Structures* Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  *Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function* Zorn et al.; App. Phys. A, 65, 333-339 (1997)  AZ  Examiner  Date Considered 2/3/07  Examiner		<del></del> _				DREIGN PATENT DOCUMENTS						
AQ  AR  AS  AT  AU  DTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  Whigh Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AW  "High Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AX  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  "Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zom et al.; App. Phys. A, 65, 333-339 (1997)  AZ  AZ  AZ  AZ  Additional References sheet(s) attached batched whether or not citation is in conformance with MPEP 609; Draw line through citation if not in						COUNTRY						
AQ  AR  AS  AT  AU  DTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  Whigh Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AW  "High Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AX  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  "Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zom et al.; App. Phys. A, 65, 333-339 (1997)  AZ  AZ  AZ  AZ  Additional References sheet(s) attached batched whether or not citation is in conformance with MPEP 609; Draw line through citation if not in			AO		<b></b>			<u> </u>				
AR  AS  AT  AU  AV  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  Whigh Precision UV-Visible-Near IR Stokes Vector Spectroscopy, Zettle et al.; Thin Solid Films, 234 (1993)  AX  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  "Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339  (1997)  AZ  AZ  AZ  Additional References sheet(s) attached by the pertinent properties of the InP(001) by the pertinent pages, etc.)  AB  AB  AB  AT  AD  AD  AD  AD  AD  AD  AD  AD  AD			<del>├</del>		T							
AR  AS  AT  AU  AV  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  Whigh Precision UV-Visible-Near IR Stokes Vector Spectroscopy, Zettle et al.; Thin Solid Films, 234 (1993)  AX  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  "Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339  (1997)  AZ  AZ  AZ  Additional References sheet(s) attached by the pertinent properties of the InP(001) by the pertinent pages, etc.)  AB  AB  AB  AT  AD  AD  AD  AD  AD  AD  AD  AD  AD	<u> </u>		AQ		† <del></del>			<u> </u>				
AS  AT  AU  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  Whigh Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AW  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  "Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zom et al.; App. Phys. A, 65, 333-339  (1997)  AZ  AZ  Date Considered 2/3/07  Examiner  Date Considered 2/3/07	-							1				
AT  AU  OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  Whigh Precision UV-Visible-Near IR Stokes Vector Spectroscopy, Zettle et al.; Thin Solid Films, 234 (1993)  AW  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  "Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339  (1997)  AZ  AZ  Additional References sheet(s) attached battle of the InP(001) Bulk and Surface Dielectric Function Zorn et al.; App. Phys. A, 65, 333-339  (1997)  AZ  Date Considered 2/3/07			<del> </del>		1							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  AW "High Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AW "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX "Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339  (1997)  AZ Additional References sheet(s) attached  Examiner  Date Considered 2/3/07					1							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  AW "High Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AW "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX "Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339 (1997)  AZ Additional References sheet(s) attached Date Considered 2/3/07  Examiner Date Considered 2/3/07	-		<del> </del>									
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  AW "High Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX "Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339 (1997)  AZ Additional References sheet(s) attached Date Considered 2/3/07  Examiner Date Considered Whether or not citation is in conformance with MPEP 609; Draw line through citation if not in	-		<del> </del>	<del> </del>								
AW "High Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)  AW "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX "Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zom et al.; App. Phys. A, 65, 333-339  (1997)  AZ Additional References sheet(s) attached  Examiner  Date Considered 2/3/07  ATT and a shell it in ference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in	-			OTHER R	EFERENCES	(Including Author, Title, Date, Pertine	nt Pages,	etc.)				
AW  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  AX  "Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).  Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function" Zom et al.; App. Phys. A, 65, 333-339 (1997)  AZ  AZ  Additional References sheet(s) attached Date Considered 2/3/07  Examiner  Date Considered 2/3/07	<u> </u>		_	T*High Precision IN-M	isible-Near IR	Stokes Vector Spectroscopy," Zettle et	al.; Thin So	olid Films, 2	234 (1993	3)		
AX **Ellipsometry on Very Thick Multilayer Students Stude	/	Th	AW									
Examiner  Date Considered 2/3/07  To relevability if references is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in	li .		AX									
Examiner  Date Considered 2/3/07  All and the state of th		m	Temperature Deopendence of the InP(001) Bulk and Surface Dielectric Function* Zom et al.; App. Phys. A, 65, 333-339									
Examiner    Examiner	AZ						dditional References sheet(s) attached					
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		caminer 2/2/7/								<del></del>		
	.E	xaminer:	Initial if	reference is considered to the considered. Include	d, whether or copy of this fo	not citation is in conformance with MPEP orm with next communication to applicant	609; Draw	/ line throu	gh citatio	n if not In		